

RELIABILITY REPORT  
FOR  
MAX44007EDT+  
PLASTIC ENCAPSULATED DEVICES

October 8, 2014

**MAXIM INTEGRATED**

160 RIO ROBLES  
SAN JOSE, CA 95134

<b>Approved by</b>
Sokhom Chum
Quality Assurance
Reliability Engineer

## Conclusion

The MAX44007EDT+ successfully meets the quality and reliability standards required of all Maxim Integrated products. In addition, Maxim Integrated's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim Integrated's quality and reliability standards.

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### I. Device Description

#### A. General

The MAX44007 ambient light sensor features an I<sup>2</sup>C digital output that is ideal for a number of portable applications such as smartphones, notebooks, and industrial sensors. At less than 1 $\mu$ A operating current, it is the lowest power ambient light sensor in the industry and features an ultra-wide 22-bit dynamic range from 0.025 lux to 104,448 lux. Low-light operation allows easy operation in dark glass applications. The on-chip photodiode's spectral response is optimized to mimic the human eye's perception of ambient light and incorporates IR and UV blocking capability. The adaptive gain block automatically selects the correct lux range to optimize the counts/lux. The IC includes two I<sup>2</sup>C slave address options: 1011 010x and 1011 011x. The IC is designed to operate from a 1.7V to 3.6V supply voltage range and consumes only 0.65 $\mu$ A in full operation. It is available in a small, 2mm x 2mm x 0.6mm UTDFN-Opto package.

## II. Manufacturing Information

A. Description/Function:	Low-Power Digital Ambient Light Sensor with Enhanced Sensitivity
B. Process:	S4
C. Number of Device Transistors:	12841
D. Fabrication Location:	California, Texas or Japan
E. Assembly Location:	Thailand, Taiwan
F. Date of Initial Production:	December 17, 2010

## III. Packaging Information

A. Package Type:	6L OPTO TDFN
B. Lead Frame:	NiPd
C. Lead Finish:	NiPd
D. Die Attach:	Conductive
E. Bondwire:	Au (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-9000-4051
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	3
J. Single Layer Theta Ja:	83.9°C/W
K. Single Layer Theta Jc:	37°C/W
L. Multi Layer Theta Ja:	N/A
M. Multi Layer Theta Jc:	N/A

## IV. Die Information

A. Dimensions:	58X38 mils
B. Passivation:	Si <sub>3</sub> N <sub>4</sub> /SiO <sub>2</sub> (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	Metal1 = 0.5 microns (as drawn)
F. Minimum Metal Spacing:	Metal1 = 0.45 microns (as drawn)
G. Bondpad Dimensions:	
H. Isolation Dielectric:	SiO <sub>2</sub>
I. Die Separation Method:	Wafer Saw

## V. Quality Assurance Information

- |                                   |   |
|-----------------------------------|---|
| A. Quality Assurance Contacts:    | Don Lipps (Manager, Reliability Engineering)<br>Bryan Preeshl (Vice President of QA)            |
| B. Outgoing Inspection Level:     | 0.1% for all electrical parameters guaranteed by the Datasheet.<br>0.1% for all Visual Defects. |
| C. Observed Outgoing Defect Rate: | < 50 ppm  |
| D. Sampling Plan:                 | Mil-Std-105D  |

## VI. Reliability Evaluation

### A. Accelerated Life Test

The results of the 135C biased (static) life test are shown in Table 1. Using these results, the Failure Rate ( $\lambda$ ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{1000 \times 4340 \times 123 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 1.72 \times 10^{-9}$$

$$\lambda = 1.72 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim Integrated's reliability monitor program. Maxim Integrated performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maximintegrated.com/qa/reliability/monitor>. Cumulative monitor data for the S4 Process results in a FIT Rate of 0.04 @ 25C and 0.69@ 55C (0.8 eV, 60% UCL).

### B. E.S.D. and Latch-Up Testing (lot SF0WAA005D, D/C 1038)

The OY44-3 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2500V per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/-250mA and overvoltage per JEDEC JESD78.

**Table 1**  
Reliability Evaluation Test Results

**MAX44007EDT+**

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
<b>Static Life Test</b> (Note 1)	Ta = 135°C	DC Parameters	78	0	TAAL5A024Q3, D/C 1246
	Biased	& functionality	45	0	TAAL5A024Q2, D/C 1246
	Time = 1000 hrs.				

Note 1: Life Test Data may represent plastic DIP qualification lots